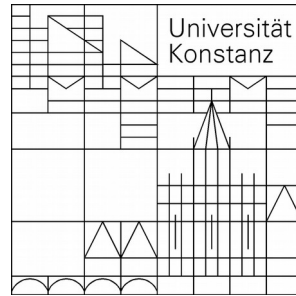


Data processing with XDS and associated programs

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Outline

- I. *XDS* – the program package
- II. *XDS* – how to obtain good data
- III. Serial crystallography – some aspects

From tomorrow – tutorial using *your* data. I leave after my talk on tuesday so pls talk to me today or tomorrow!

throughout this talk: *program*, *file*

The *XDS* program suite

Original author:
Wolfgang Kabsch
(Max-Planck-Institute
Heidelberg)

Since ~1986

I joined in 2007



The *XDS* program suite

- *XDS*: the main program (indexing, integrating, scaling)
- *XSCALE*: scale several *XDS* intensity data sets together; zero-dose extrapolation; statistics
- *XDSCONV*: convert to other programs' formats

The following programs are independent of the *XDS* distribution:

- *XDS-Viewer* - inspect diagnostic images written by *XDS*, or (single) data frames (open source: sourceforge.net). Instead, *adxv* may be used
- *XDSTAT* - additional statistics (not part of main distribution; download and use: see XDSwiki)
- *XDSGUI* – graphical user interface (open source: sourceforge.net) for *XDS* and *SHELX C/D/E* (since latest version)

Distribution for 64bit Linux & Mac: latest VERSION: Jan-2018 (w/ last error correction BUILT 8-Aug-2018); <http://xds.mpimf-heidelberg.mpg.de/>; see XDSwiki: Installation.

interfaced to ...

- beamline software (generating **XDS.INP**)
- scripts: *xia2* (CCP4), *autoPROC* (Globalphasing), *xdsme* (Soleil), *autoxds* (SSRL), *autoprocess* (CMCF), ...
generate_XDS.INP (XDSwiki), *fast_dp* (Diamond) - *please cite XDS!*
- CCP4: *pointless*, *xdsconv* (type CCP4_I+F, or CCP4, or CCP4_I, or CCP4_F)

XDSGUI

- Simple GUI using Qt
- Adapted to the XDS philosophy
- User – extensible / modifiable commands
- Plots synchronously while processing
- Documentation and availability: XDSwiki

Sources of information

- XDS main website: <http://xds.mpimf-heidelberg.mpg.de> - complete, accurate, up-to-date documentation; download
- XDSwiki:
http://strucbio.biologie.uni-konstanz.de/xdswiki/index.php/Main_Page
- CCP4 bulletin board
- “XDS webinar” (<http://www.rigaku.com/downloads/webinars/kay-diederichs/>)
- “X-ray tutorial” (Faust *et al.* JAC 2008, 2010)
- Email to kay.diederichs@uni-konstanz.de

*XD*Swiki

- started Feb 2008; ~ 60 pages at
http://strucbio.biologie.uni-konstanz.de/xdswiki/index.php/Main_Page
 - e.g. „Optimization“; explanations of task output
 - „Tips and Tricks“, „FAQ“
 - „Quality Control“ with datasets and results, and links to the projects of the ACA2011 and ACA2014 „data processing“ workshop
 - anybody can contribute!
- (same holds for CCP4wiki: ~ 90 pages at
http://strucbio.biologie.uni-konstanz.de/ccp4wiki/index.php/Main_Page)

XDS features

(just a short selection)

- 3D integration – partials/fullies implicit; fine ϕ slicing
- 3D profiles of reflections are transformed into their own coordinate systems which makes them highly similar (Kabsch 1988 *J. Appl. Cryst.* **21**, 916-924)
- Smooth scaling
- Zero-dose extrapolation (*XSCALE*) can help a lot in sub-structure determination (Diederichs *et al.* 2003, *Acta Cryst.* **D59**, 903-909.)
- Fast - two levels of parallelization

XDS non-features

- Old-fashioned: ASCII output to files, graphics, no mouse-over „help“ bubbles
- Not automatic, user is in full control
- Geometry not read from data frame headers
- Incomplete space-group determination – enough information to process data (see „Space group determination“ in XDSwiki)
- No support organization, XDS workshops, advertising, funding, income (Max Planck society)
- Source code not publicly available - but papers document features thoroughly

XDS philosophy

(just a short selection)

- Do very little, but do it very well: gives good data
- Very robust – small molecule to ribosome
- Structure and information flow easily understandable; thoroughly documented

Data processing steps

- set up geometric corrections: XYCORR
- find background and gain: INIT
- find reflection positions for indexing: COLSPOT
- index - establish cell and lattice): IDXREF
- [optional] strategy for data collection: XPLAN
- find shadowed areas on detector: DEFPIX
- evaluate intensities on all frames: INTEGRATE
- scale and calculate statistics: CORRECT

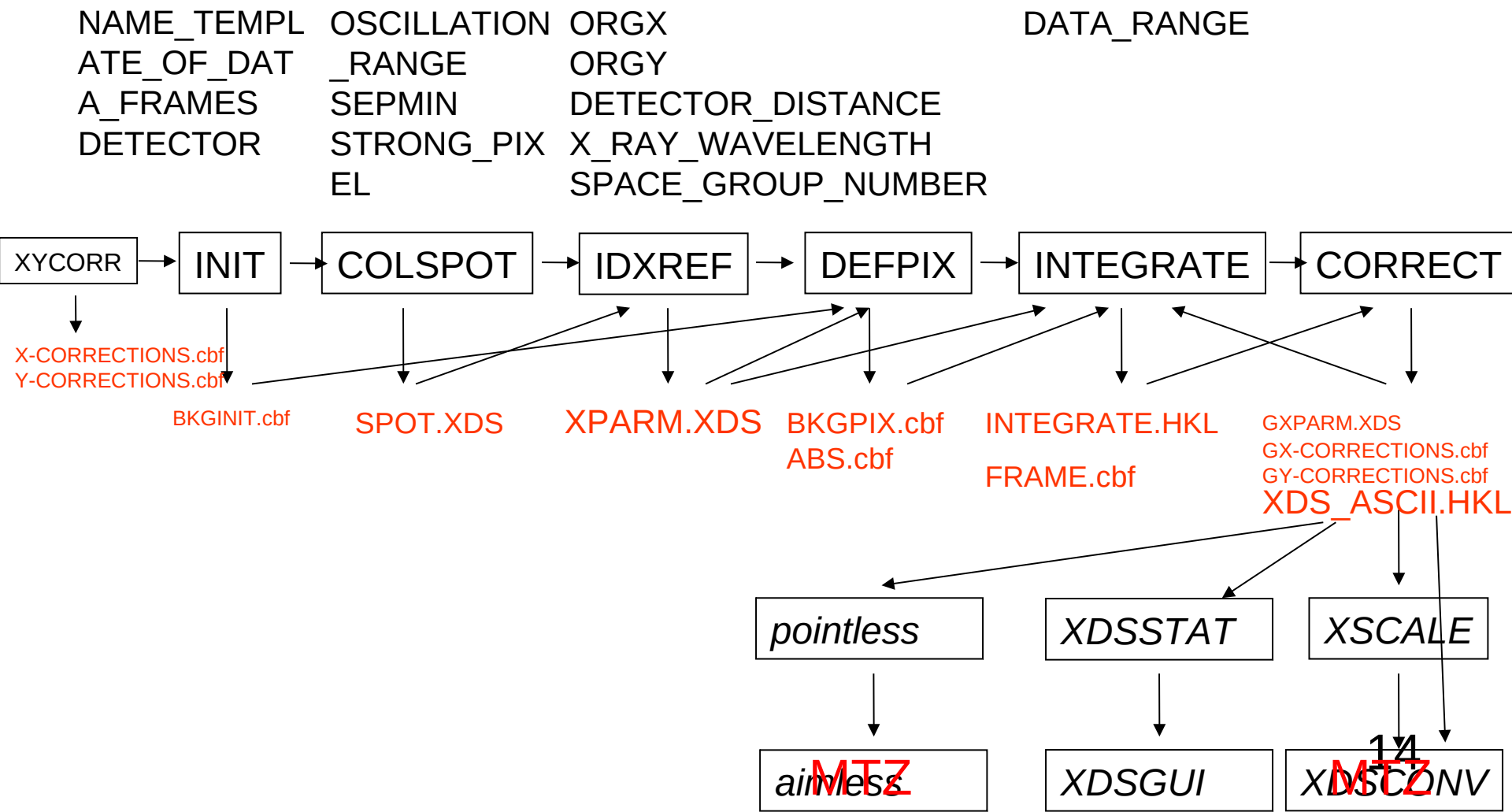
Principle of *XDS* processing

- There is one JOB= line in *XDS.INP* which specifies a list of tasks:

JOB= XYCORR INIT COLSPOT IDXREF DEFPIX INTEGRATE CORRECT

- data reduction is divided into tasks in a **modular** way
- information storage/exchange/flow between tasks by data files which may be inspected/analyzed
- each task needs the result from the previous tasks
- fine-tuning of a task does *not* require previous tasks to be repeated
- each task writes its output file *<TASK>.LP*

Information flow



```

!FORMAT=XDS_ASCII    MERGE=FALSE    FRIEDEL'S_LAW=TRUE
!OUTPUT_FILE=XDS_ASCII.HKL          DATE= 3-Oct-2006
!Generated by CORRECT    (XDS VERSION  August 18, 2006)
!PROFILE_FITTING= TRUE
!SPACE_GROUP_NUMBER=    92
!UNIT_CELL_CONSTANTS=    57.71    57.71    150.08    90.000    90.000    90.000
!NAME_TEMPLATE_OF_DATA_FRAMES= ../series_2_?????.img
!DATA_RANGE=            1        399
!X-RAY_WAVELENGTH=    0.939010
!INCIDENT_BEAM_DIRECTION= 0.001872 -0.002230  1.064947
!FRACTION_OF_POLARIZATION= 0.980
!POLARIZATION_PLANE_NORMAL= 0.000000  1.000000  0.000000
!ROTATION_AXIS=    0.999995  0.002477 -0.001917
!OSCILLATION_RANGE=    0.500000
!STARTING_ANGLE=    30.000
!STARTING_FRAME=        1
!DETECTOR=ADSC
!DIRECTION_OF_DETECTOR_X-AXIS=    1.00000    0.00000    0.00000
!DIRECTION_OF_DETECTOR_Y-AXIS=    0.00000    1.00000    0.00000
!DETECTOR_DISTANCE=    189.286
!ORGX=    1541.25  ORGY=    1535.30
!NX=    3072  NY=    3072    QX=    0.102600  QY=    0.102600
!NUMBER_OF_ITEMS_IN_EACH_DATA_RECORD=12
!ITEM_H=1
!ITEM_K=2
!ITEM_L=3
!ITEM_IOBS=4
!ITEM_SIGMA(IOBS)=5
!ITEM_XD=6
!ITEM_YD=7
!ITEM_ZD=8
!ITEM_RLP=9
!ITEM_PEAK=10
!ITEM_CORR=11
!ITEM_PSI=12
!END_OF_HEADER

```

0	0	4	4.287E-01	2.814E-01	1501.6	1514.4	99.4	0.00920	100	27	75.39
0	0	-4	2.243E-01	2.386E-01	1587.4	1548.6	91.6	0.00920	100	30	-79.02
0	0	5	5.976E-03	3.443E-01	1490.9	1510.2	100.4	0.01150	100	22	74.94

XDS output file:
XDS_ASCII.HKL

II. Getting the best data

How do random and systematic *error* depend on the *signal*?

random error obeys *Poisson statistics*
error = square root of signal

Systematic error is *proportional* to signal
error = x * signal (e.g. x=0.02 ... 0.10)

(which is why James Holton calls it „fractional error“; there are exceptions)

Systematic errors (noise)

- beam flicker (instability) in flux or direction
- shutter jitter
- vibration due to cryo stream
- split reflections, secondary lattice(s), ice
- absorption from crystal and loop
- radiation damage
- detector calibration and inhomogeneity; overload
- shadows on detector
- deadtime in shutterless mode
- imperfect assumptions about the experiment and its geometric parameters in the processing software
- ...

The “error model”

Random error: $\sigma_r(I) \approx \sqrt{I}$

this is what INTEGRATE calculates

Systematic errors: $\sigma_s(I) \approx I$

this leads to deviations $> \sigma_r(I)$ between sym-related reflections

New $\sigma(I)$ estimate: $\sigma(I) = \sqrt{a * (\sigma_r(I))^2 + b * I^2}$

with constants a,b fitted by CORRECT for the dataset

When random error vanishes (“asymptotically”),
this results in $I/\sigma(I) = 1/\sqrt{a*b}$

A *proxy* for good data

$(I/\sigma)_{\text{asymptotic}} = \text{ISa}$ (reported in **CORRECT.LP**) is a measure of systematic error arising from beamline, crystal, and data processing

For a given data set, ISa increases: if the geometric parameterization is improved; if the correct choice of “FRIEDEL'S_LAW=TRUE” versus “FALSE” is made; if BEAM_DIVERGENCE and REFLECTING_RANGE are correct. In short: when the experimental data are well processed

ISa is (other than R_{meas}) independent of random error

Maximizing ISa (good values are 30 and higher) means minimizing systematic errors;

This usually also optimizes $CC_{1/2}$ at high resolution

III. Serial crystallography, and analysis of non-isomorphism

Xtallography requires merging of data

Small crystals → low signal → small rotation range → multiple data sets

- A) medium-sized crystals - conventional
multiple (~2-10) complete data sets ($>90^\circ$ rotation)
- B) small crystals - serial synchrotron xtallography (SSX)
~20-1000 incomplete data sets ($1-20^\circ$ rotation)
- C) tiny crystals - XFEL
~200-100.000 incomplete data sets (0° rotation:
stills)

When merging data, one has to worry about non-isomorphism!

- Data sets can differ in several ways
- A single value – like R-factor - does not express this
- It is useful to consider a data set as a point in a low-dimensional space

Two types of systematic errors/differences

- Some kinds of systematic errors (e.g. beam intensity fluctuation, crystal vibration) “average out” with high multiplicity: let’s call these “isomorphous systematic errors”
- Other systematic errors (better: differences) between crystallographic data sets lead to “non-isomorphism” (*)
 - Indexing ambiguity (occurs in almost every third project)
 - Cell parameters (which anyway are not determined precisely)
 - Radiation damage (within or between data sets)
 - Composition of crystal (ligands, HA, Se, ...)
 - Conformation of molecules / loops / sidechains

* Other fields call these systematic differences “heterogeneity”

Crystallographic example: two forms of lysozyme



3aw6

3aw7

RH: 84.2%

vs 71.9%

RMSD = 0.18 Å

$\Delta\text{cell} \sim 1\%$

$R_{\text{iso}} = 44.5\%$

What does a correlation coefficient tell us?

$$cc_{xy} = \frac{\sum (x_i - \bar{x})(y_i - \bar{y})}{\sqrt{\sum (x_i - \bar{x})^2 \sum (y_i - \bar{y})^2}} \quad ; \quad -1 \leq cc_{xy} \leq 1$$

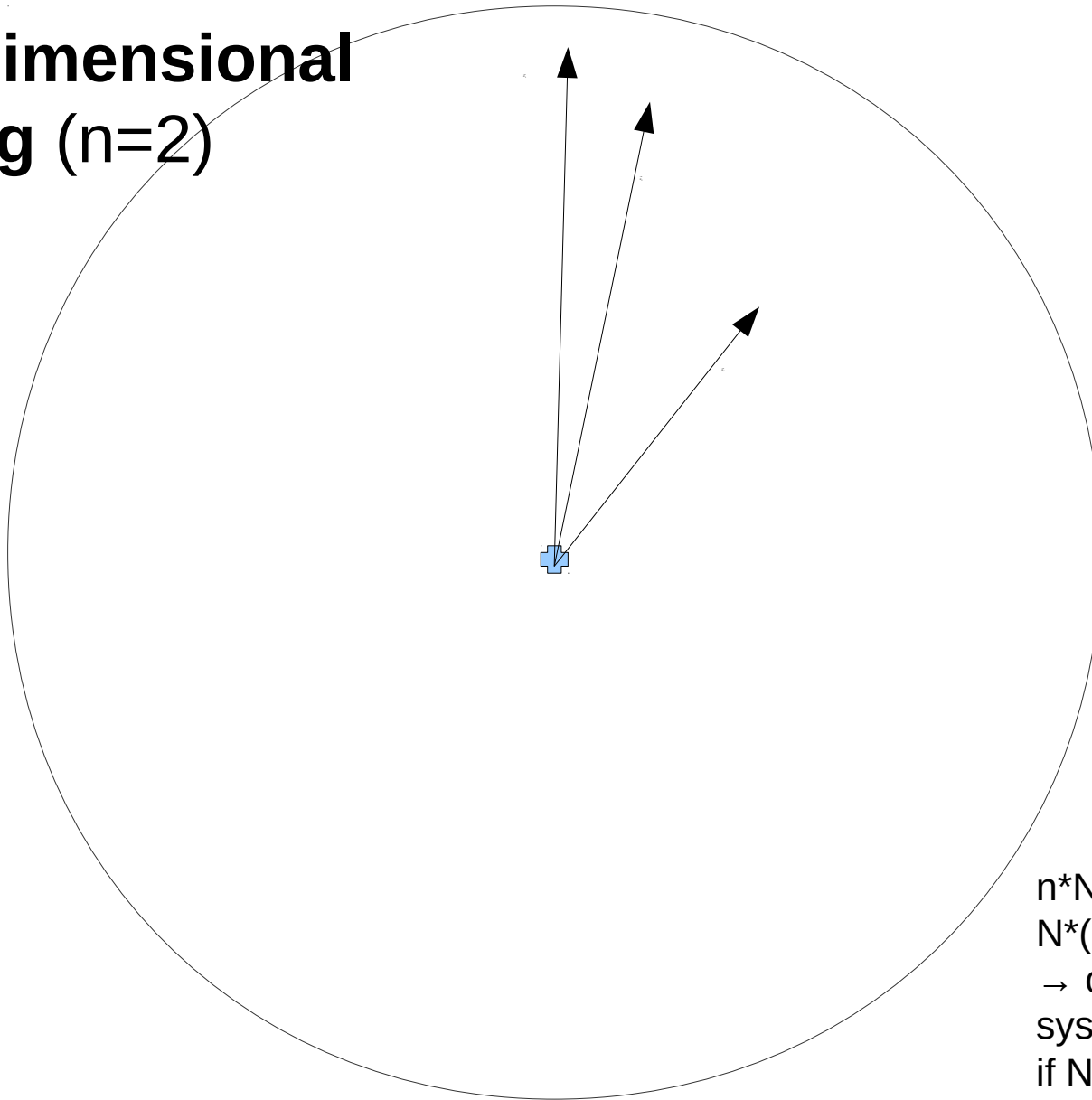
- 1) high (+ or -) correlation coefficients: data sets agree well (- : except for sign)
- 2) low correlation coefficient: data sets agree poorly

Possible reasons for 2):

- strong data, but high non-isomorphism
- weak data, and good isomorphism

These two possibilities cannot be distinguished – a single correlation coefficient doesn't tell!

Multidimensional scaling (n=2)



$$\vec{x}_1 * \vec{x}_2 = CC_{12}$$

$$\vec{x}_1 * \vec{x}_3 = CC_{13}$$

$$\vec{x}_2 * \vec{x}_3 = CC_{23}$$

....

....

....

$n*N$ unknowns
 $N*(N-1)/2$ knowns
→ overdetermined
system of equations
if $N > 2*n+1$

Analysing heterogeneity (non-isomorphism)

It can be shown (Diederichs 2017, Acta D73, 286-293) that ...

- the least-squares solution of $\phi(\{\vec{x}\}) = \sum_{i>j} (cc_{ij} - \vec{x}_i \cdot \vec{x}_j)^2$ exists and is "unique" if cc_{ij} known
- it can be obtained from the n Eigenvalues/Eigenvectors of the cc_{ij} matrix
- the $\mathbf{x}$ vectors are arranged in a sphere with radius 1, in n -dimensional space

Amount of signal

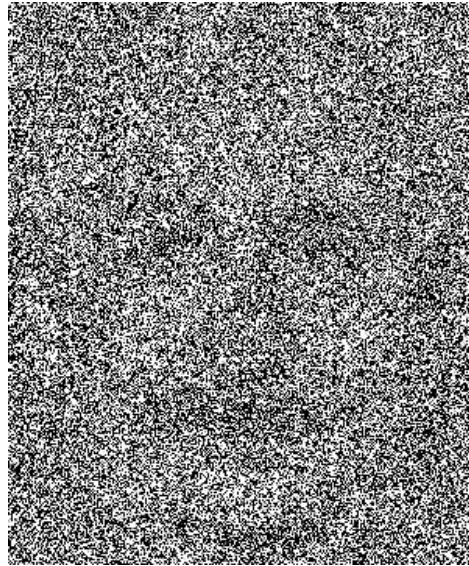
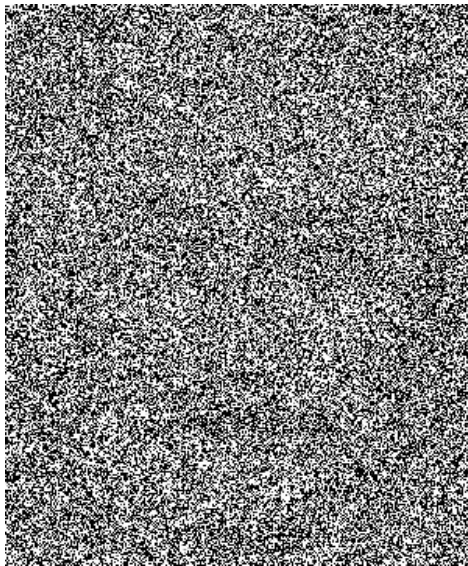
- the length of a vector is CC^* , the correlation with its prototype ("true") dataset, and depends on the *random and isomorphous systematic error* of the data
- Data sets that are isomorphous have vectors with same direction
- CC^* may also be calculated from $CC_{1/2}$, if multiple observations in a dataset are available

Relation between datasets

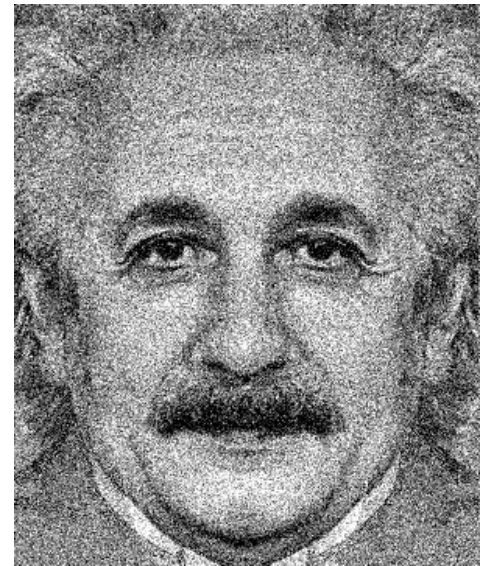
- angle between x_i and x_j : *non-isomorphous systematic difference* of i and j
- $cc_{ij} = CC^*_i \cdot CC^*_j \cdot \cos(\text{angle}(x_i, x_j))$ ("equation 5" in paper)

The procedure separates the isomorphous from the non-isomorphous differences!

Example: two kinds of noisy images



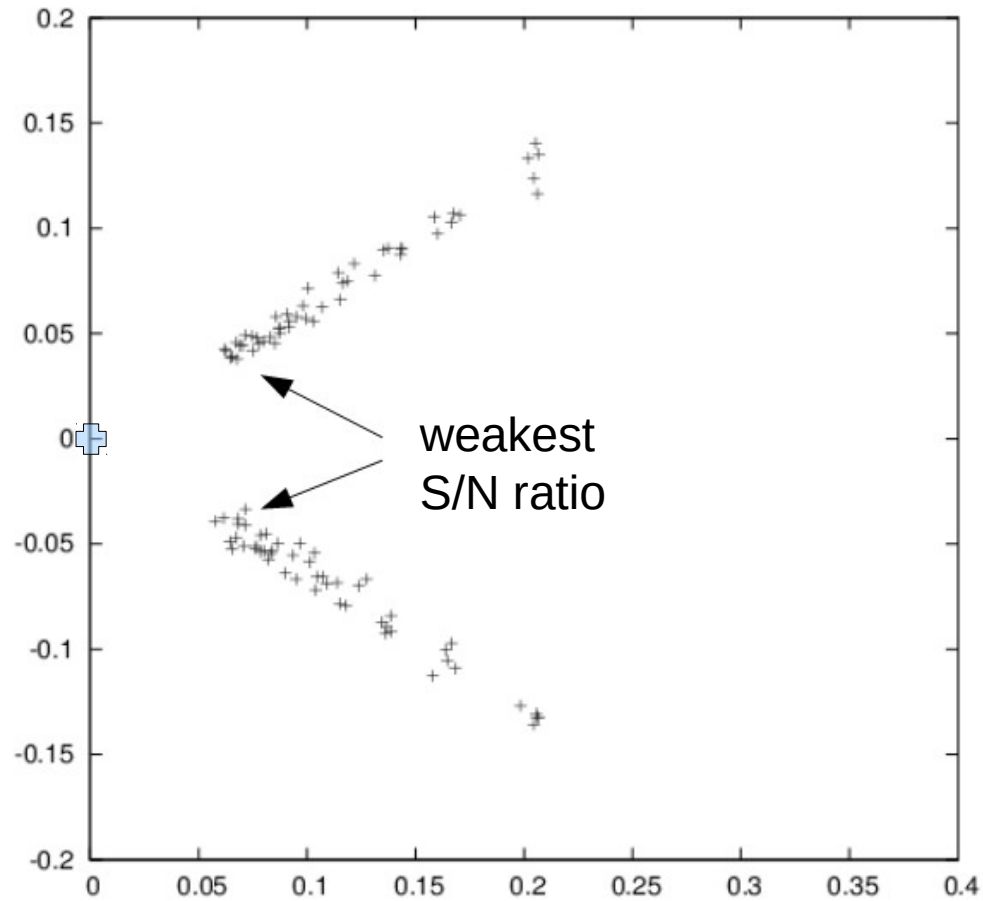
50+50
→



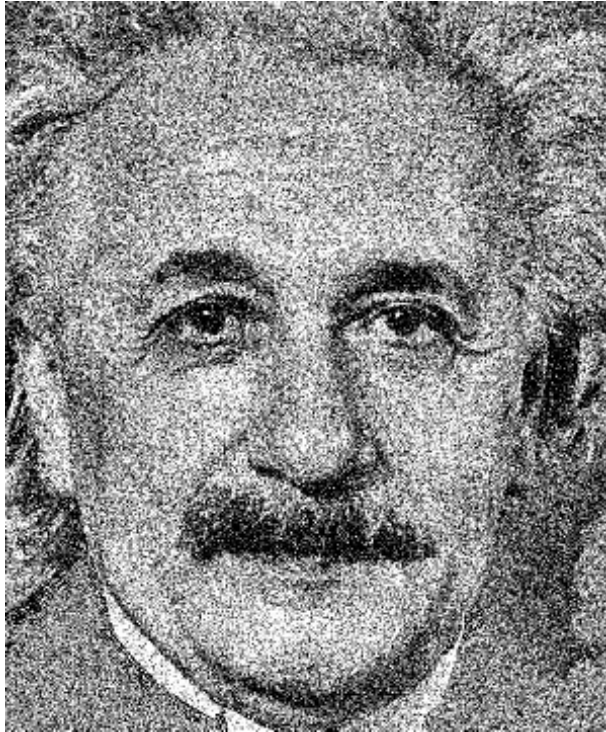
**noisy images (SNR=1/13
and SNR=1/9) of original
and mirror picture**

**Result of averaging
without knowledge
whether original
image, or its mirror**

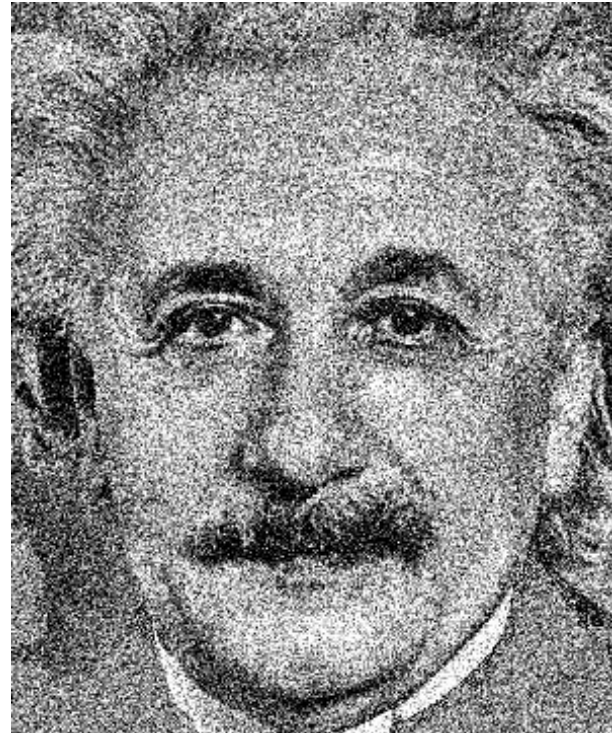
CC analysis with $n=2$



Removing the ambiguity



**Result of
averaging: original**

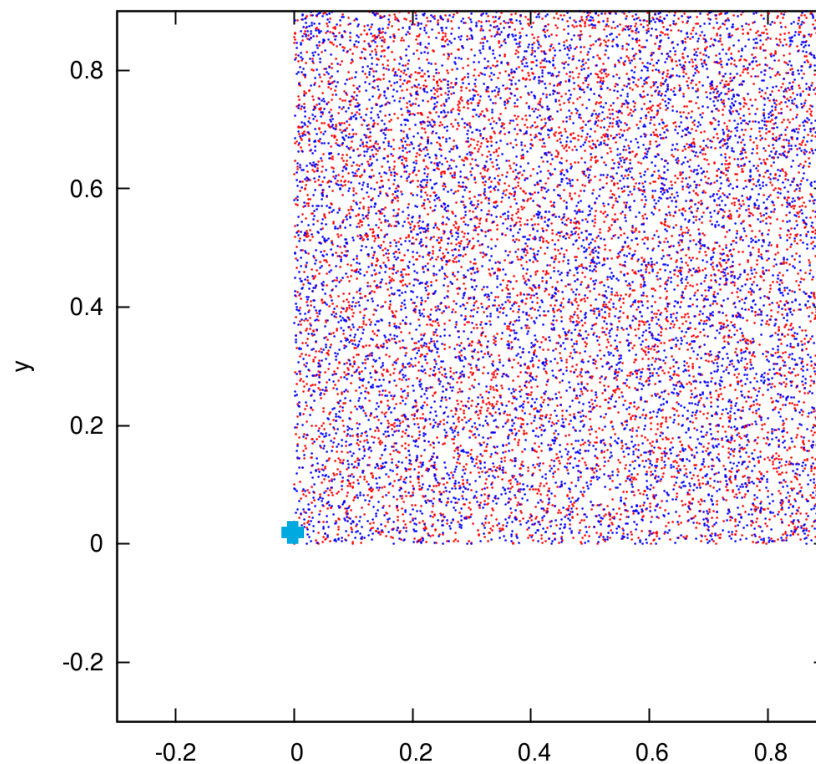


**Result of
averaging: mirror**

Programs

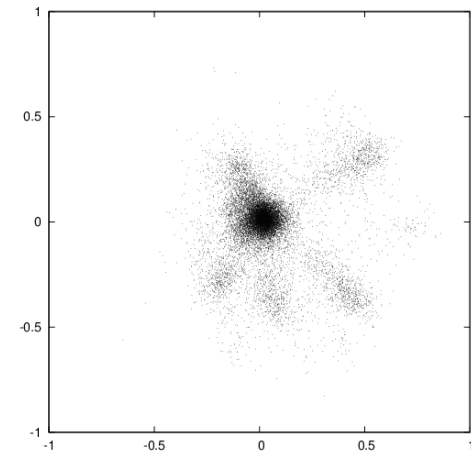
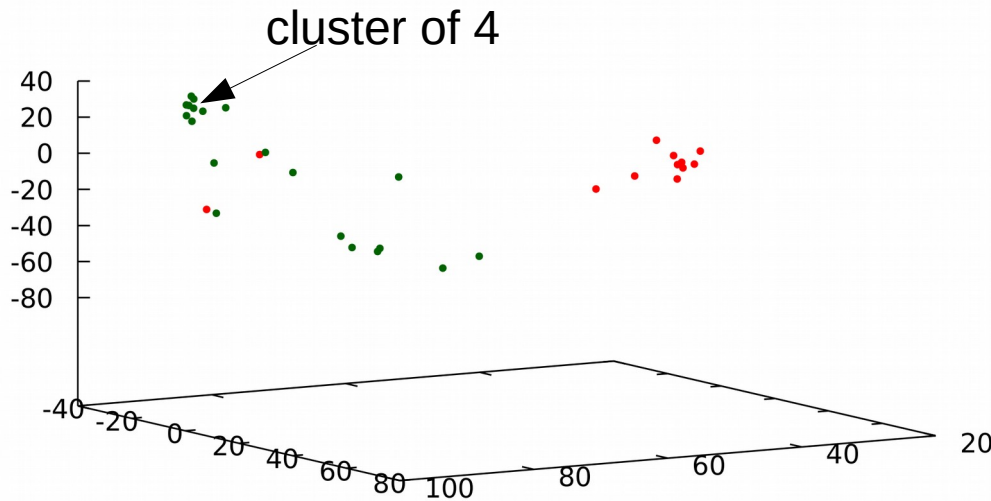
- **XDS** used for data processing of n **partial** data sets with common cell parameters & spacegroup
 - completeness: angular coverage / spacegroup
 - $I\sigma_a$: a measure of systematic error (**need**
 - $CC_{1/2}$: a measure of precision **multiplicity!**)
 - XDS_ASCII.HKL: reflection file
- **XSCALE** scales & merges all n XDS_ASCII.HKL files together
 - adjusts the error model to achieve consistency
 - statistics as XDS
- **XSCALE_ISOCLUSTER**: $\rightarrow$ iso.pdb; n atoms representing n data sets tentatively cluster; write XSCALE.#.INP files for clusters
- **XDSCC12**: analyze individual data sets by calculating their influence on $CC_{1/2}$ / $CC_{1/2}$ ano. Optimize $CC_{1/2}$ by removing datasets that decrease $CC_{1/2}$ – this is called “delta- $CC_{1/2}$ -method” (Assmann 2016)
- **XDS_NONISOMORPHISM**: analyze complete datasets using equation 2

PS-I (N=15445, n=2) [Chapman 2011]



Least-squares iterations starting from random positions -
each point represents a dataset with one of two indexing modes

Examples: conventional / XFEL

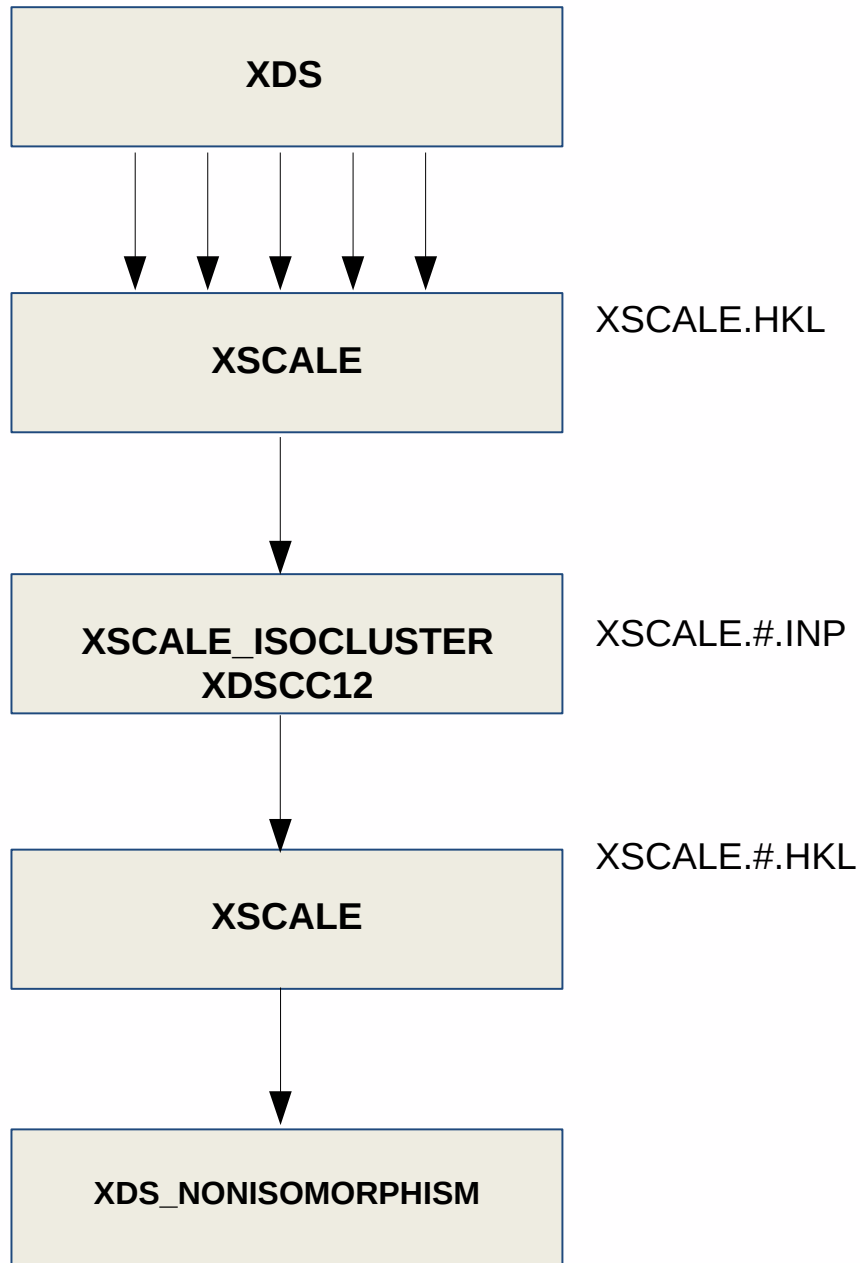


Data from Knott, East-Seletsky, Cofsky, Holton, Charles, O'Connell and Doundna (2017) Guide-bound structures of an RNA-targeting A-cleaving CRISPR-Cas13a enzyme. *Nature Structural & Molecular Biology* 24, 825–833

XFEL : PS-I (N=15445, n=3)
after removing the indexing ambiguity

output:

explanation:



first time: use all datasets
(`MINIMUM_I/SIGMA=0` or `1`)

separate into clusters & rank

specify cluster to work with: (e.g.)
`ln -s XSCALE.1.INP XSCALE.INP`
possibly iterate with
`XSCALE_ISOCLUSTER`

Use equation 2 to quantify coordinate
differences between datasets

Serial xtallography: Summary

- Analyse relations between data sets: quantify isomorphous errors and non-isomorphism
- **Potential to identify clusters of data sets with biological meaning/relevance**
- A method that separates homogeneous (isomorphous) and heterogeneous (non-isomorphous) differences between data sets in (user-defined) low-dimensional space
- The axes of low-dimensional space are not "labelled" with specific properties
- Applications in Structural Biology: crystallographic datasets, or images of molecules
- (Analogously applicable in other Sciences: spectra, expression patterns, sequences, ...
 - wherever correlation coefficients between noisy data sets are available)

References

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